ABSTRACT

A semiconductor tester comprising a driver circuit for generating a predetermined driver waveform without using a coil device. The driver circuit provided in a pin electronics receives a waveform-shaped signal to be supplied to an IC pin of a device under test (DUT) and converts the amplitude to an amplitude of predetermined level. The driver output pulse outputted from the output terminal of the driver and having the converted amplitude to the IC pin of the DUT. The tester has pulse compensating means for compensating the individual waveforms of the rising and falling edges of the driver output pulse in a predetermined way.